

Notic of Referenc s Cited	Application/Control No. 09/866,576	Applicant(s)/Patent Under Reexamination OHMI ET AL.	
	Examiner Douglas W Owens	Art Unit 2811	Page 1 of 1

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	B	US-6,034,418 ✓	03-2000	Matsuura	257/632
	C	US-6,117,749 ✓	09-2000	Aronowitz et al.	438/454
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NON-PATENT DOCUMENTS

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	U	Stephen A. Campbell, 1996. Oxford University Press. The Science and Engineering of Microelectronic Fabrication. pages 29-31 and 394-396 ✓
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.